

Search Notes

Application/Control No.

10/761,297

Examiner

Sisay Yacob

Applicant(s)/Patent under
Reexamination

SUN, BEN-CHANG

Art Unit

2612

SEARCHED

Class	Subclass	Date	Examiner
341	22	8/30/2006	S.Y.
341	23, 26	8/30/2006	S.Y.
345	172	8/30/2006	S.Y.
345	171, 173	8/30/2006	S.Y.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched EAST US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	8/30/2006	S.Y.